



lightlab

We measure for your projects

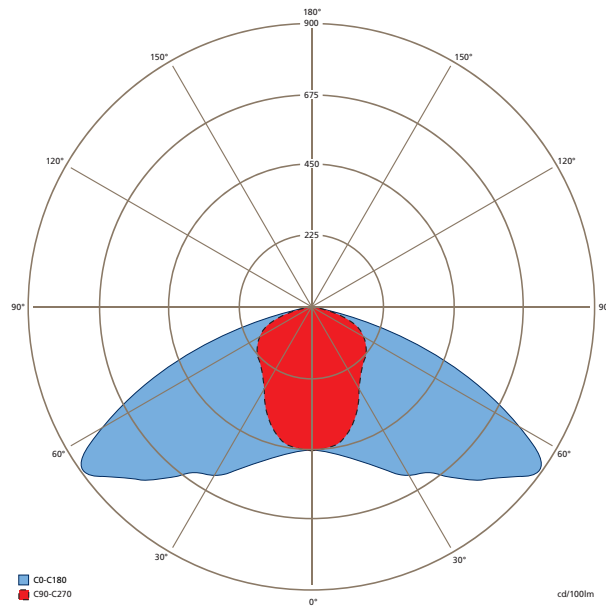
Whenever a project starts, is in process or ends, measurements of components or optical systems are essential. opsira measures the necessary optical values for you in several light measurement laboratories and provides significant measurement data and test reports. The measurements are carried out by means of traceably calibrated detectors and documented in detail.

From the simple measurement of a surface reflection through complex scattering light distributions to far-field luminous intensity distributions – you will receive your data shortly and can continue your project or include the data into your sales information.

There are some examples of measurements carried out in the opsira lightlabs overleaf.

opsira

www.opsira.com/lightlab



Measurements of the opsira lightlab

OMS-PHI-ST	Measurement of the total luminous flux (integrating sphere)
OMS-S-ST	Measurement of relative and/or absolute spectra (IR, VIS and UV) and calculation of all conventional color parameters such as chromaticity coordinates (X, Y, Z, x, y, u, v, u', v', L*a*b, Lab99), color temperature, color rendering indices, color saturation, hue angle, dominant wavelength and peak wavelength
OMS-LVK-ST (OMS-EUL)	Measurement of the far field luminous intensity distribution and calculation of the total luminous flux (generation of far field files such as EULUMDAT and IES)
OMS-EULSYM	Symmetrization of the measurement data around symmetrical axes or planes
OMS-KLD	Cone beam chart generation
OMS-LWG	Determination of the luminaire light output ratio (goniophotometer)
OMS-LMW	Calculation of the luminous flux efficiency factor in lm/W and the energy efficiency grade
OMS-LVK-ST	Measurement of the far field radiant intensity distribution
OMS-LVK-SPR	Measurement of the luminous intensity and spectral distribution
OMS-E-ST	Measurement of the illuminance
OMS-I-ST	Measurement of the luminous intensity
OMS-I-LL	Measurement of the in-plane illuminance distribution respectively luminous intensity distribution (camera-based)
OMS-L-ST	Measurement of the luminance
OMS-LVK-L	Measurement of the far field luminous intensity distribution and calculation of the average luminance
OMS-L-K	Measurement of the luminance in a climate chamber
OMS-RS-ST	Measurement of ray data (photometric)
OMS-RS-FARB	Extension of the rayset file by one color (polychromatic)
OMS-TR	Measurement of transmission or reflection of material samples (e.g. glass, plastic, aluminum, leather, fabric etc.) in 1-D
OMS-ST-IP	Measurement of the in-plane scattering light behavior of material samples (in-plane)
OMS-ST-3D	Angle-resolved scattering light measurement (BSDF, BRDF, BTDF) of material samples (3-D) at various incident angles
OMS-STR	Measurement of the spectral transmission or reflection of one material sample by means of integrating sphere
OMS-ST-3D-SPR	Measurement of the spectral transmission and reflection of material samples (3-D) at various incident angles
OMS-RSE	Measurement of the relative spectral response of a photo detector
OMS-EVK	Measurement of the spatial reception distribution of a detector (e.g. cosine characteristics)

Further measurement types on request.